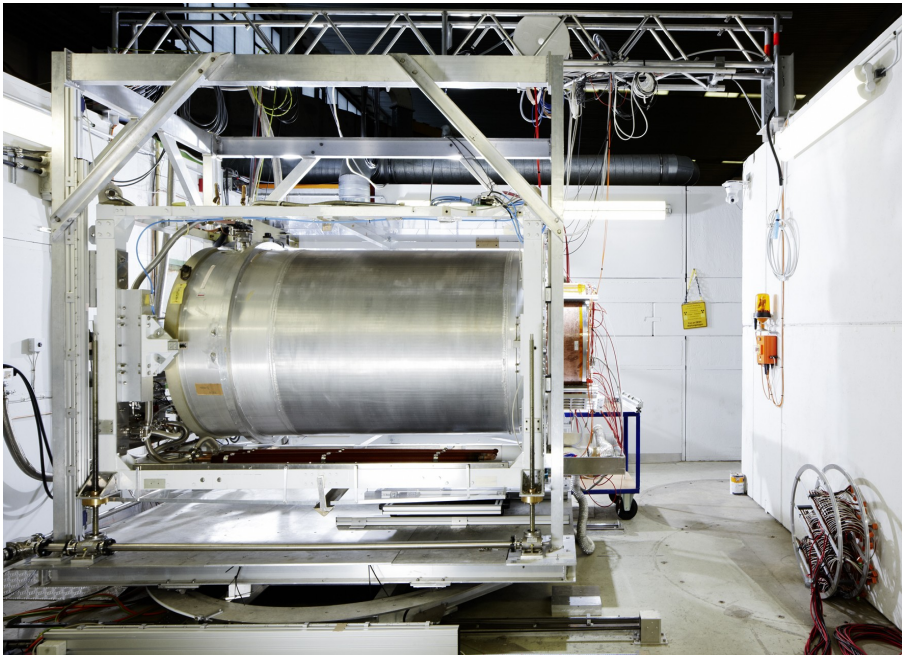


# Investigations of the long-term stability of a GEM-TPC

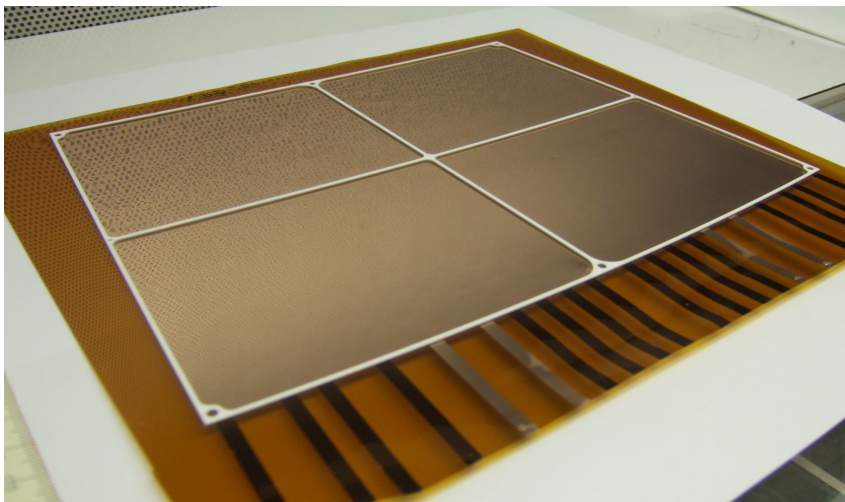
Oleksiy Fedorchuk  
FLC TPC group  
2016, Hamburg



# Goal of the Study

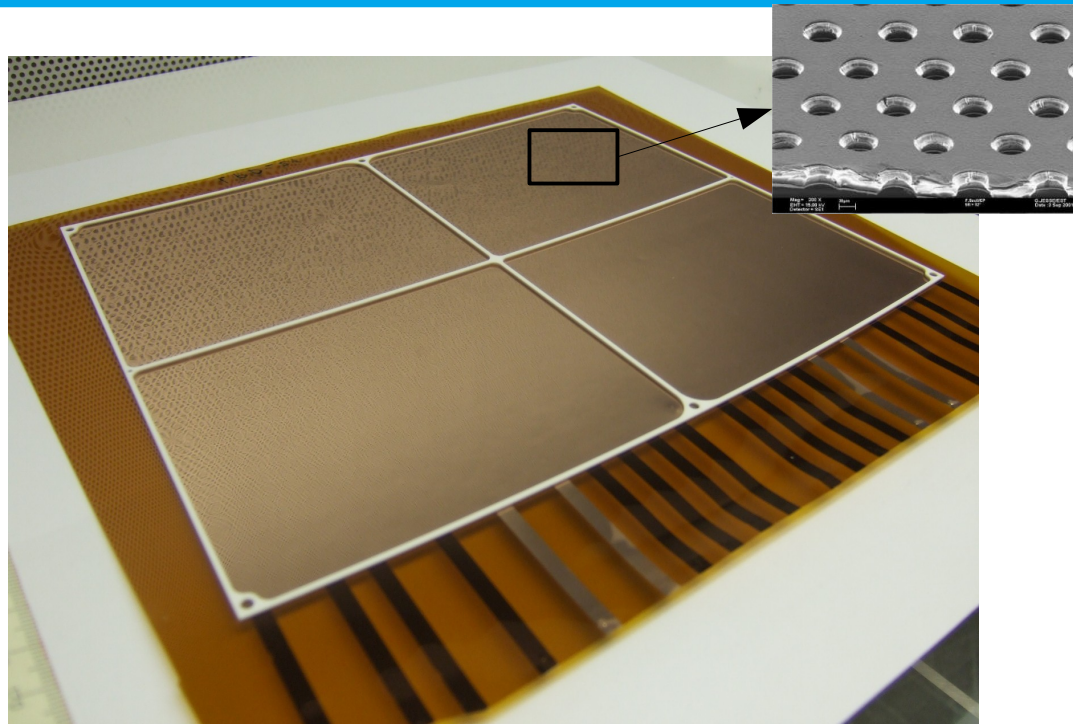


- Have built and operated TPC with triple GEM readout
- Test beam in March 2013 and later in Fall 2013 showed a problem with the high voltage long-term stability
- After several weeks of stable operation
  - Several observed discharges
  - 2 destructive discharges at the end of Test Beam
  - 1 destructive discharges which extreme conditions

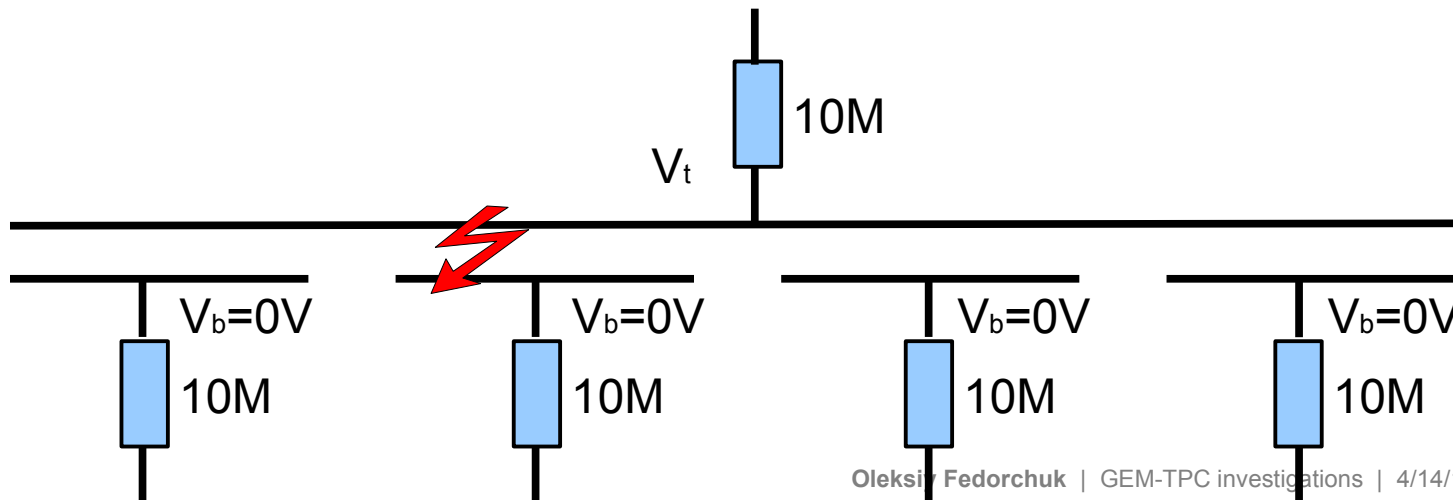


- **Goals of this study:**
  - Study the discharge process
  - Understand the cause of GEM destruction
  - Find the way to increase GEM resistance to destructive consequences of a discharge

# GEM structure and connection

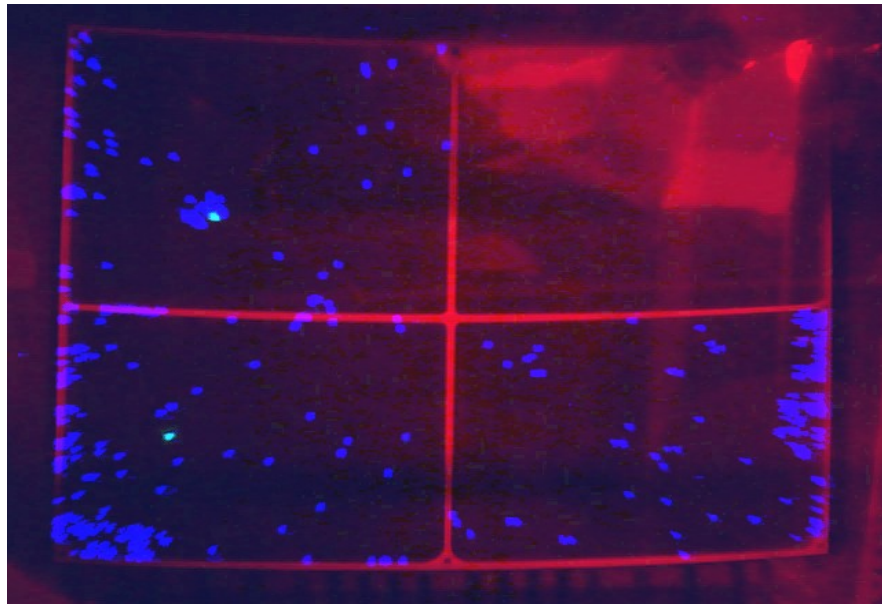


- previous experience with smaller (10x10) GEMs showed no problem
- study in detail the larger modules
- note: all measurements are based on small statistics of destroyed GEMs, drawing conclusions is difficult



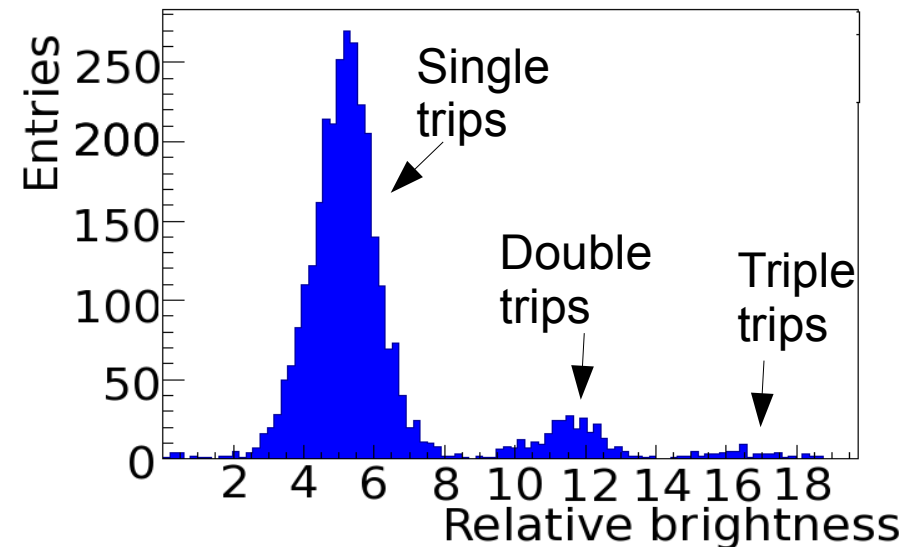


# Experimental setup (**EXTRAME CONDITIONS USED**)



- We built a system to observe the light produced by discharges
- Light integrated over couple of thousands discharges
- $U=650V$  instead of 250V or 360V

## Discharges light intensity

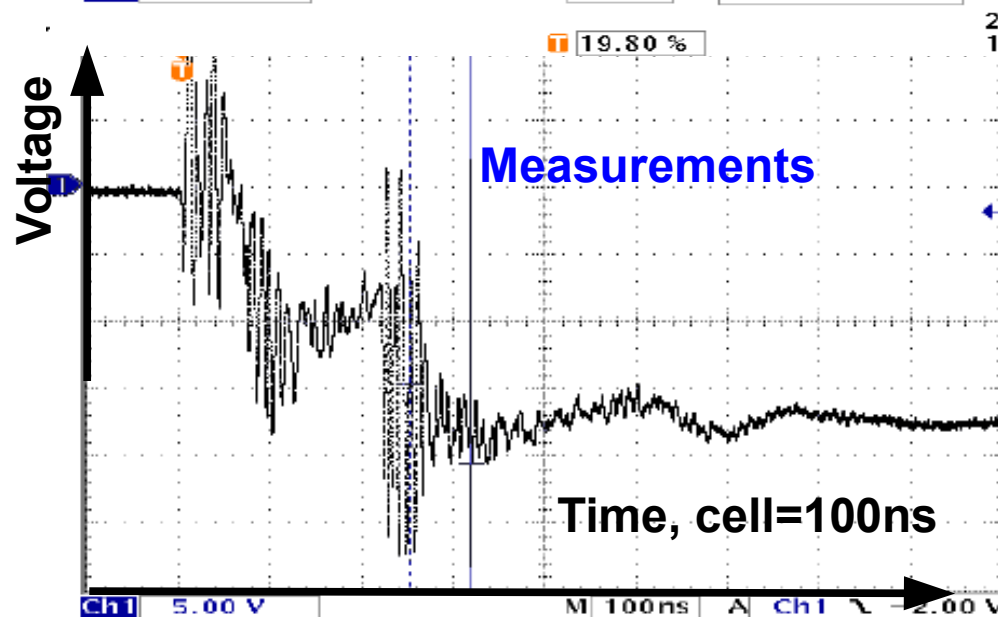
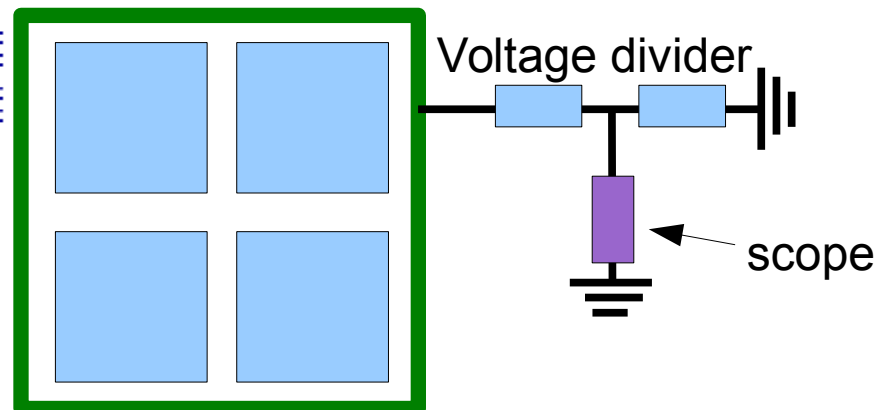
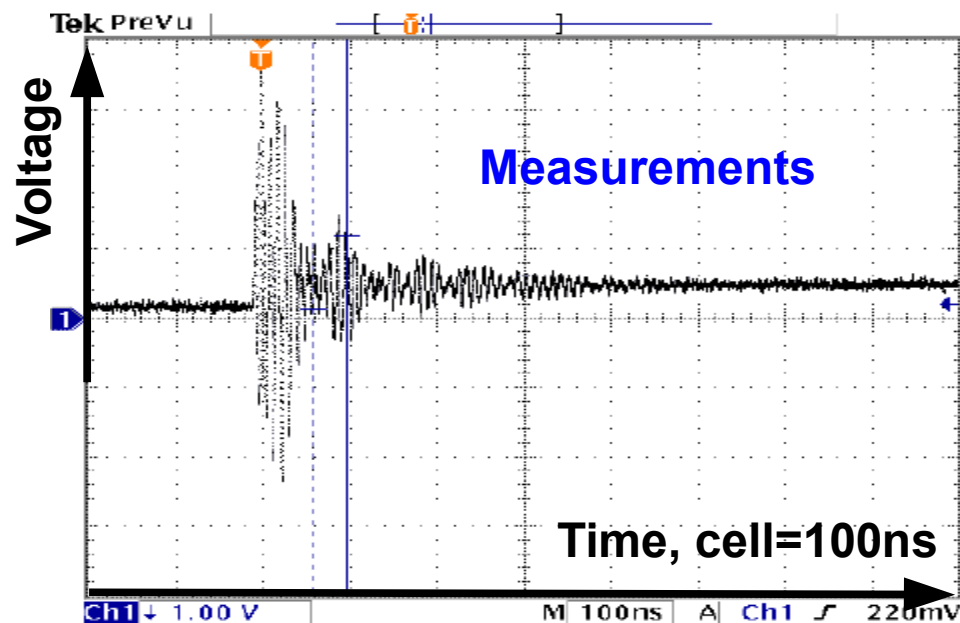


- **observe multiple discharges: They happen in different sectors (within one time frame of 33ms)**





# Oscilloscope measurements

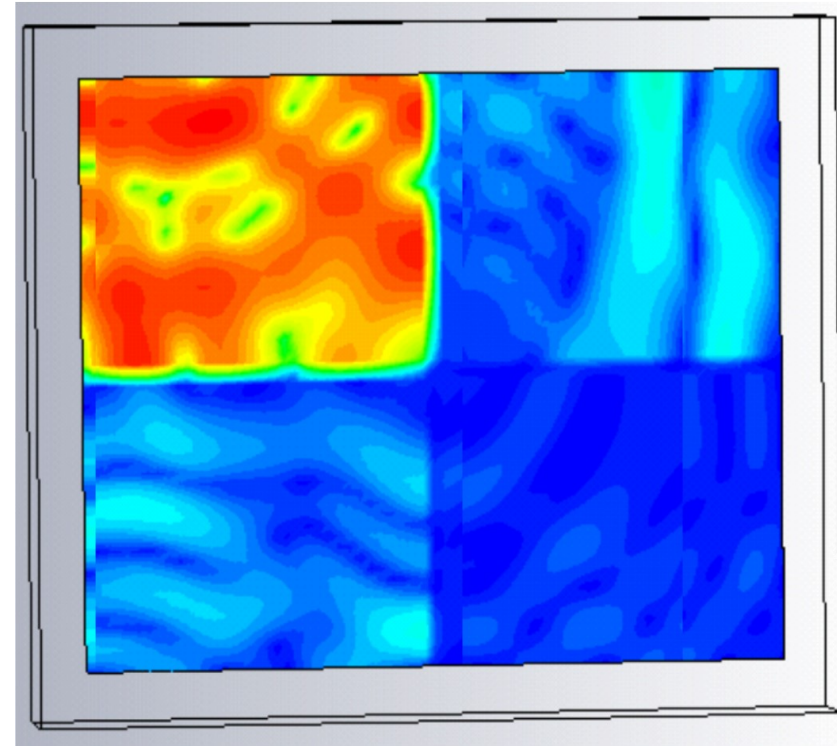
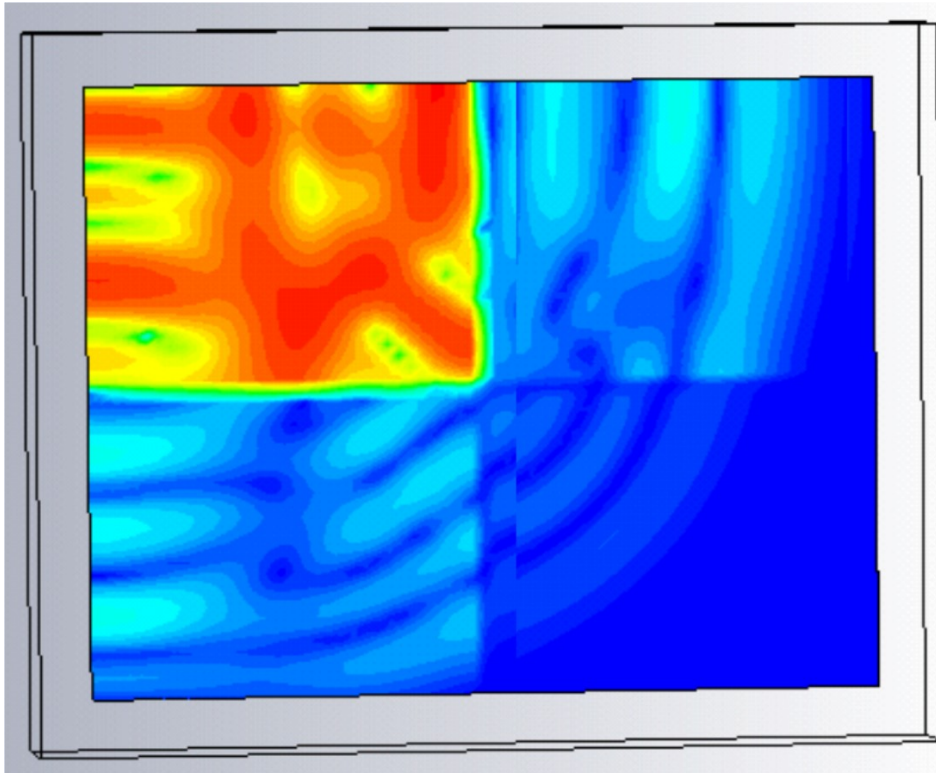


24 Apr 2015  
11:14:19  
Δ: 5.80 V  
@: -20.7 V  
Δ: 68.0ns  
@: 316ns

- we observe oscillations of the potential after a spark
- we observe a clear sequential behavior of multiple discharges
- we suspect that the oscillations enhance the probability for multiple discharges

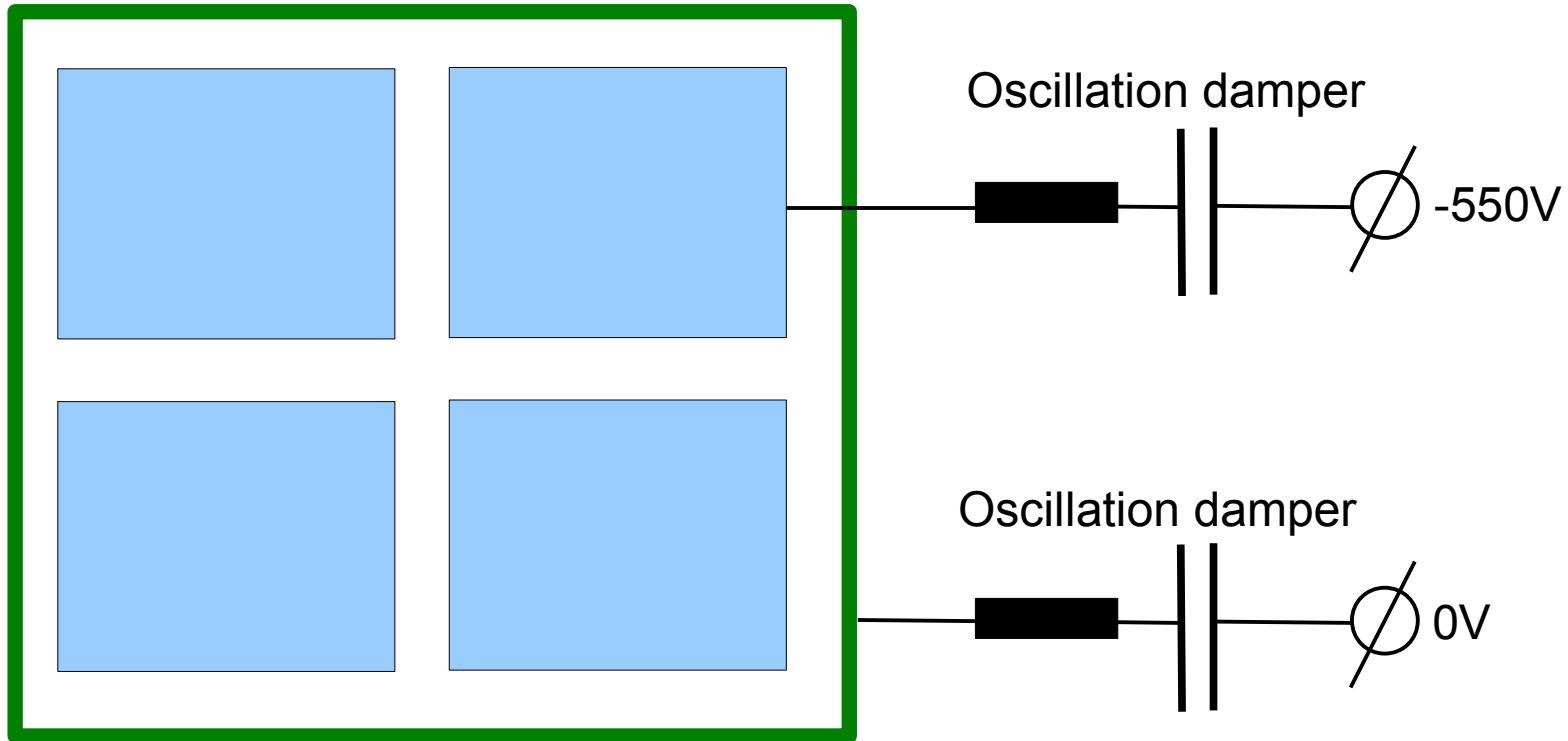
# Discharge simulations (<http://desy.de/~fedorch/Oscil/>)

- Discharge causes current oscillations on GEM surface in different sectors (CST<sup>®</sup> simulations)



- **Voltage oscillations caused by electromagnetic wave reflected from borders.**

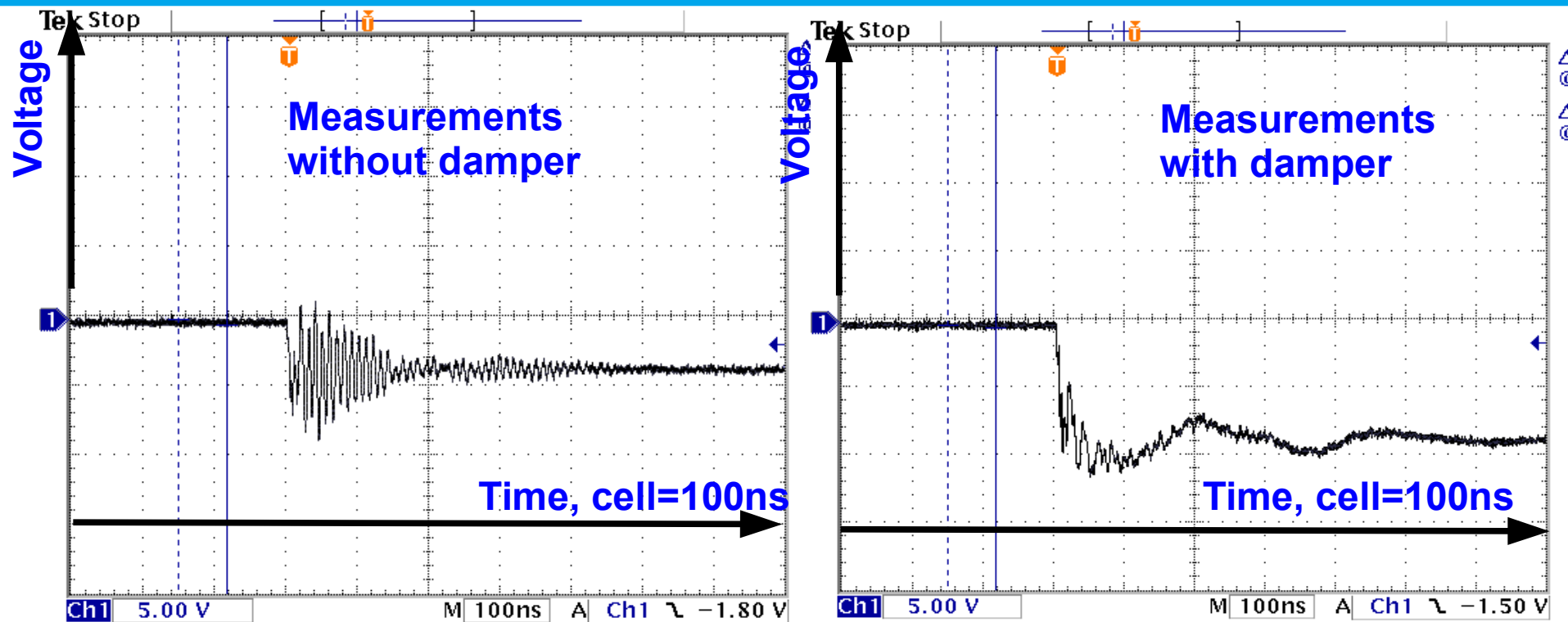
# Oscillations damper



- Introduce a damping circuit to damp out the peaks of the oscillations
- Goal is to drain the oscillations from the module faster to avoid triggering discharges in other sectors



# Filter implementation experimental effect (neighbor sector)



520V	Without RC (22hours)	With RC (47hours)	Without RC again (63hours)
Registered discharges	166	75	75
Multy discharges among	13	0	5

➤ **Filtering of oscillations helps to get rid of multiple discharges**



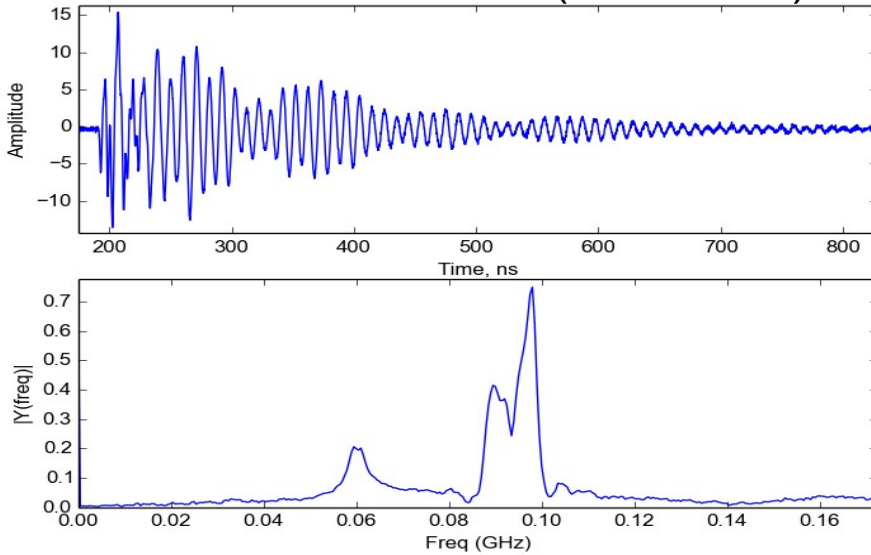
# Intermediate conclusions

- We see multiple discharges ( $\sim 100\text{ns}$  time difference).
- We see and simulate voltage oscillations directly after a discharge.
- The oscillations are triggered by a discharge in one GEM
- We see evidence that introducing a filter (damper) can significantly reduce the multiple discharge rate
- **However:**
  - **we have never been able to connect destructive discharges with**
  - **multiple discharges. They are most likely not the cause of the destruction**
  - **However this does not prove that oscillations do not take a part in the destruction process.**

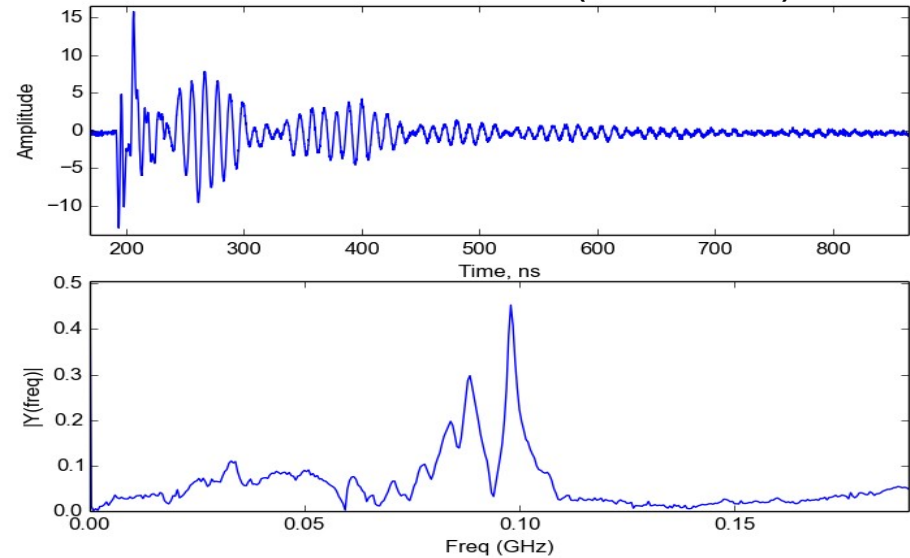


# Fourier transformation

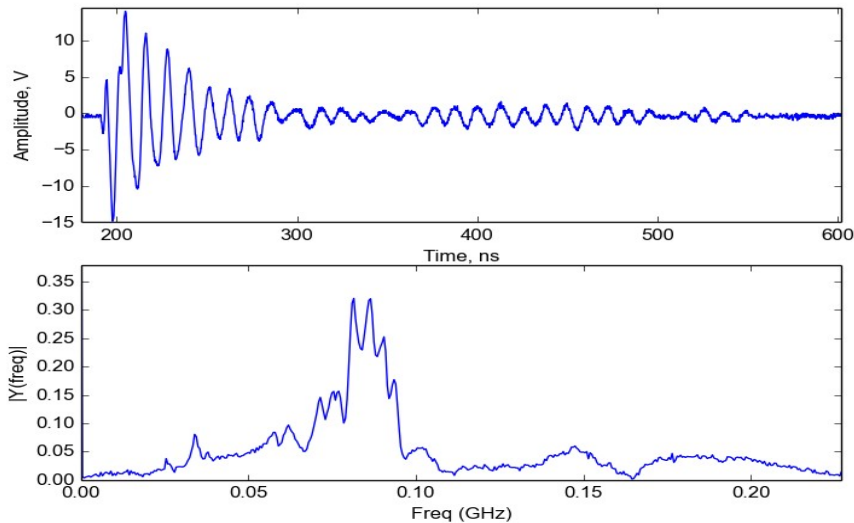
## Common electrode (~22x18cm)



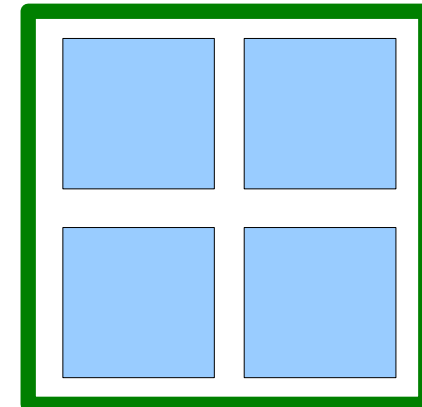
## Sector electrode (~11x9cm)



## 10x10cm GEM

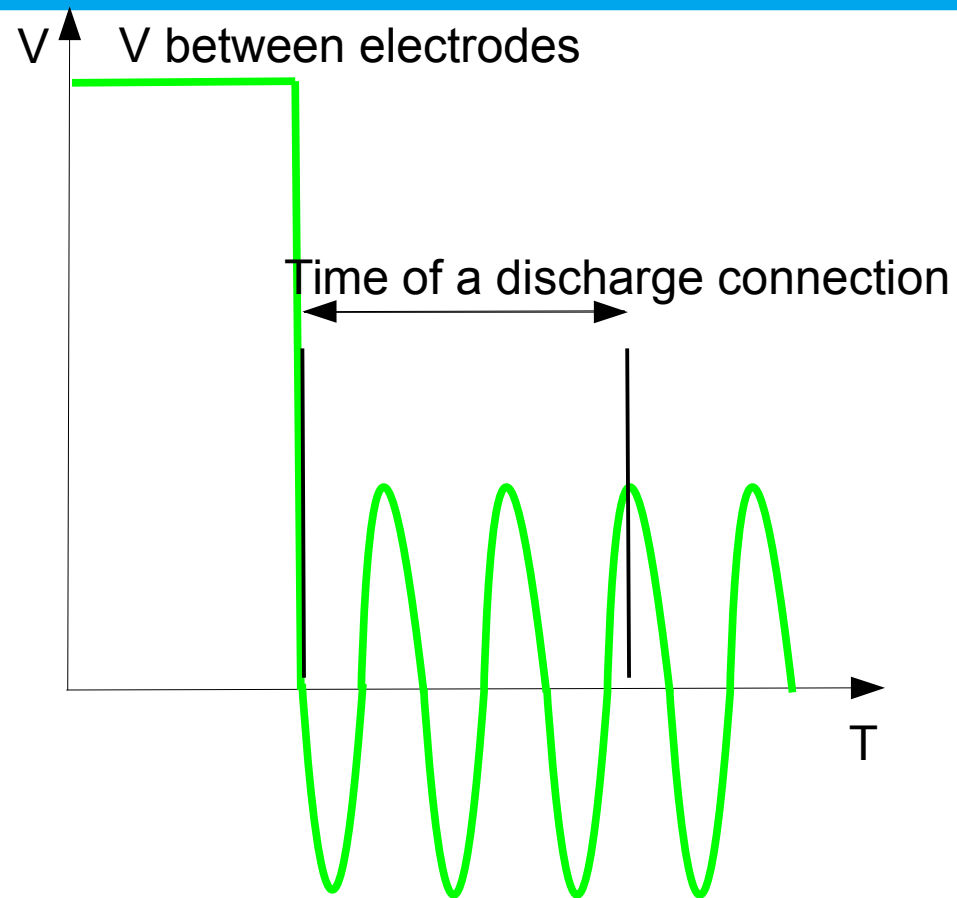
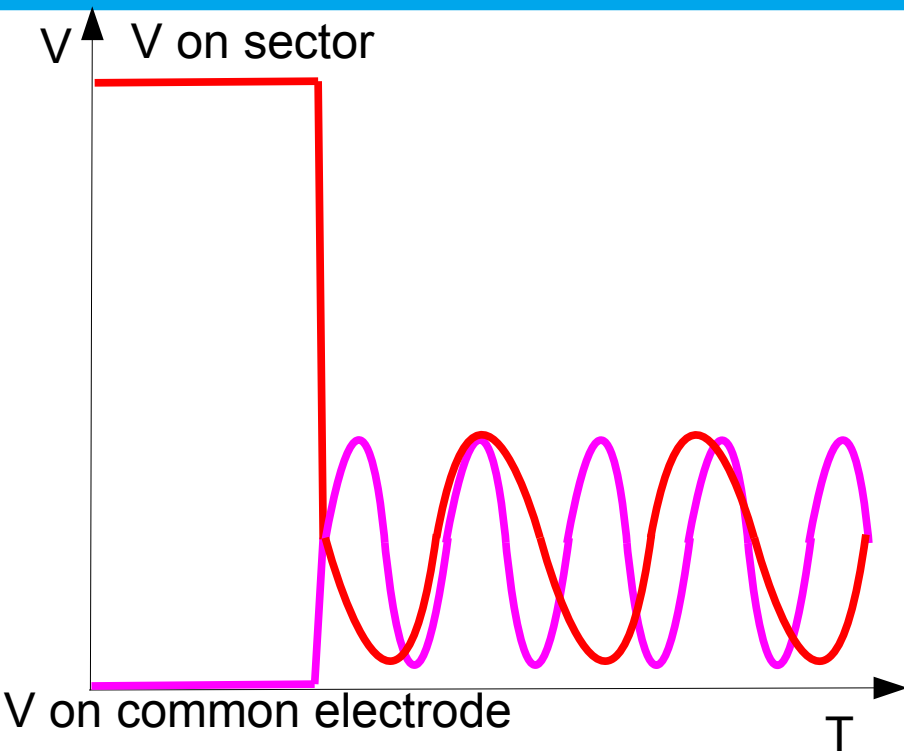


- TDS 3054b
- 500MHz bandwidth
- 5GS/s
- 50Ohm load
- 100x attenuator
- Multiple modes for single sector
- Low frequency for common



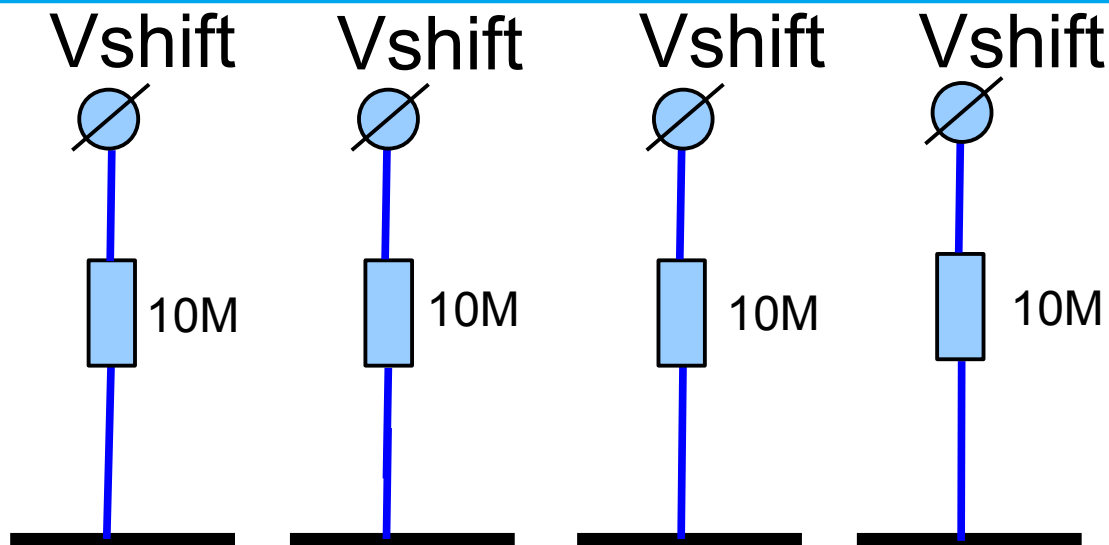


# Idea of oscillation destruction influence



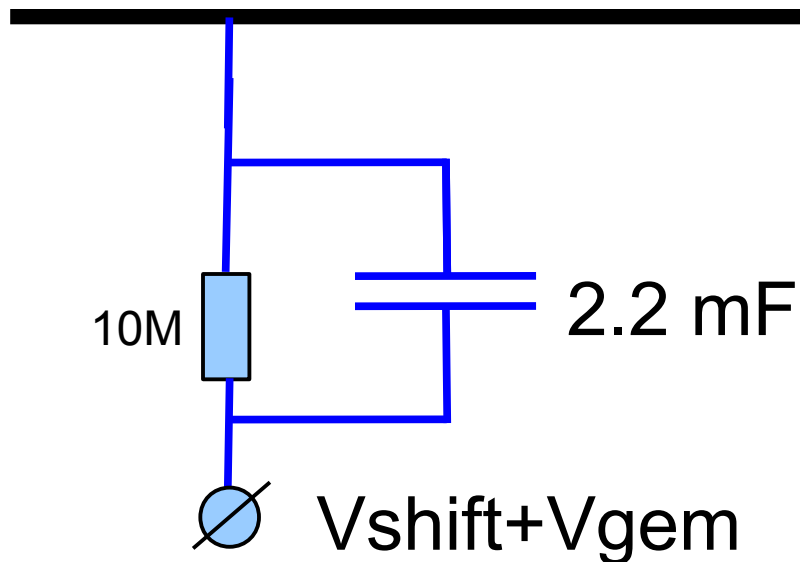
- If time of a discharge connection is higher than oscillation period ( $\sim 10\text{ns}$ ) then we have a current oscillations in discharge channel during a discharge.

# Scheme of the setup

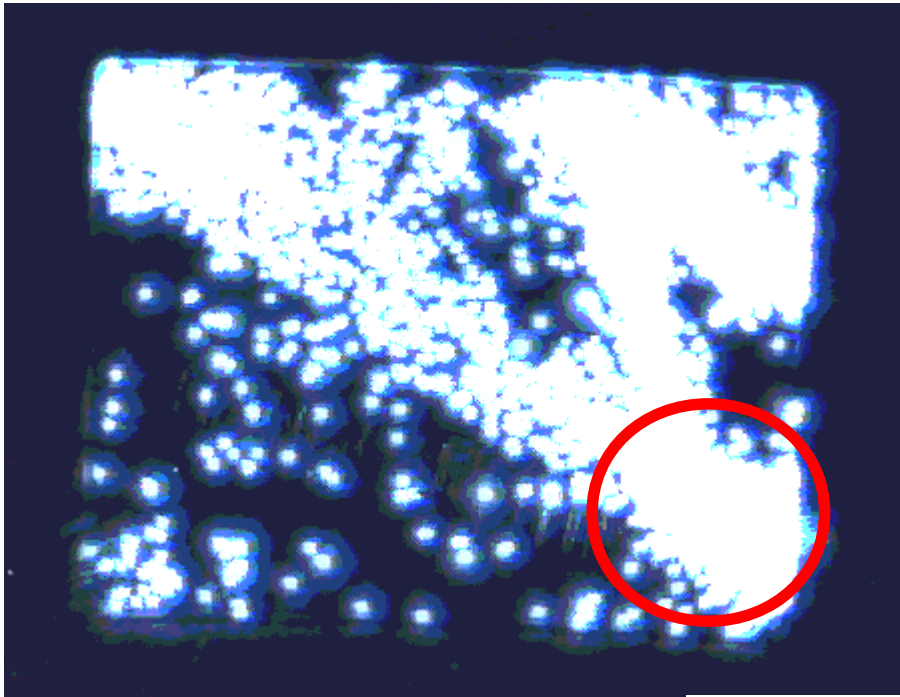


> This setup has been build after reconsidering results of lot and lot of previous measurements.

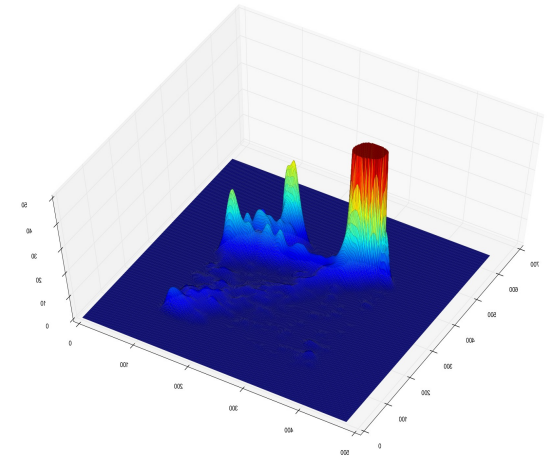
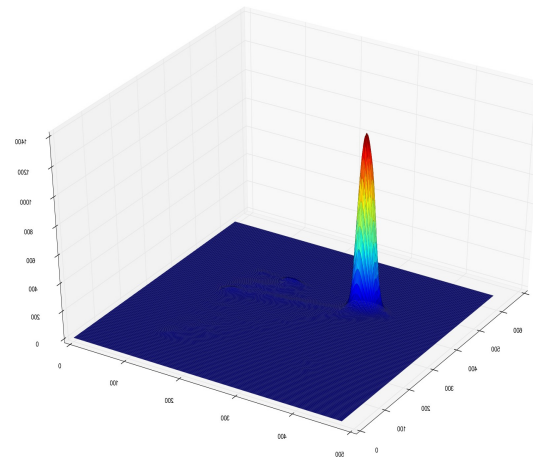
> We still try to connect oscillations and destructiveness.



# The tough guy!

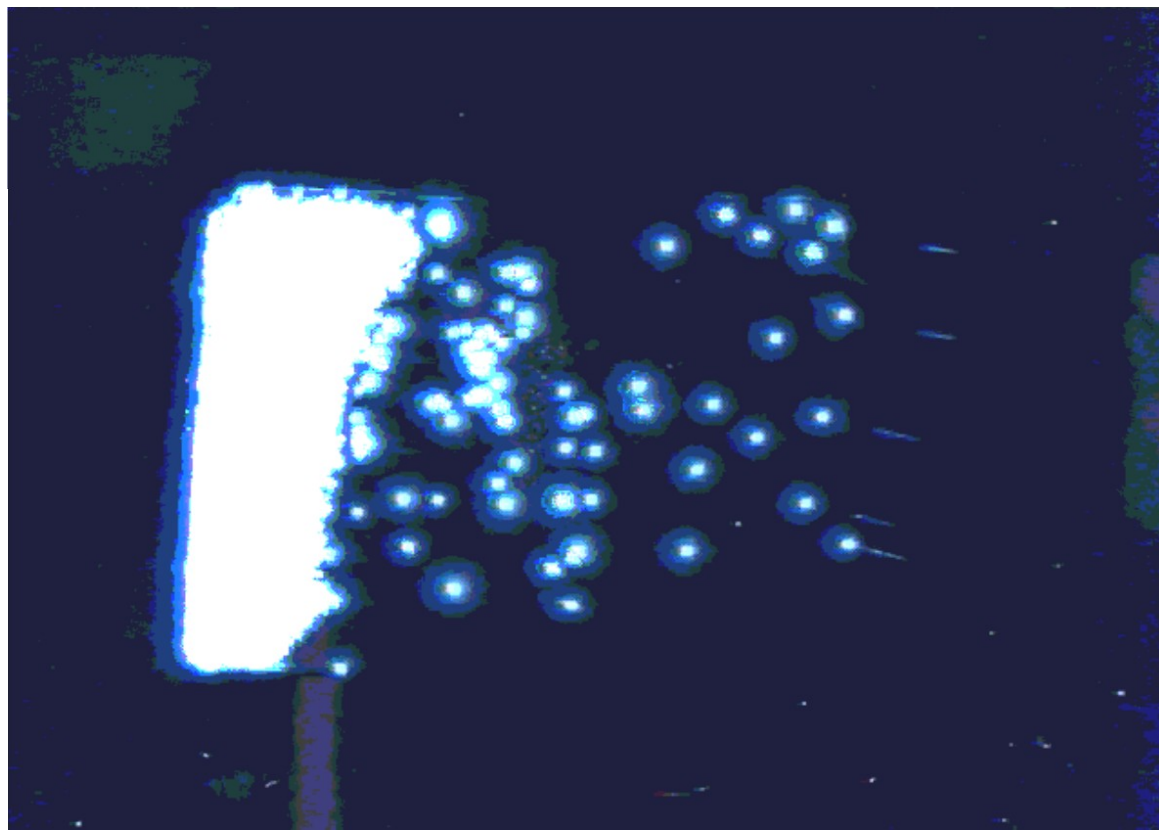


- operated double framed GEM under extreme conditions with protective circuit
- recorded about 30000 discharges
- towards the end deterioration of performance, constant current
- physical damage to the GEM observed, details are under study





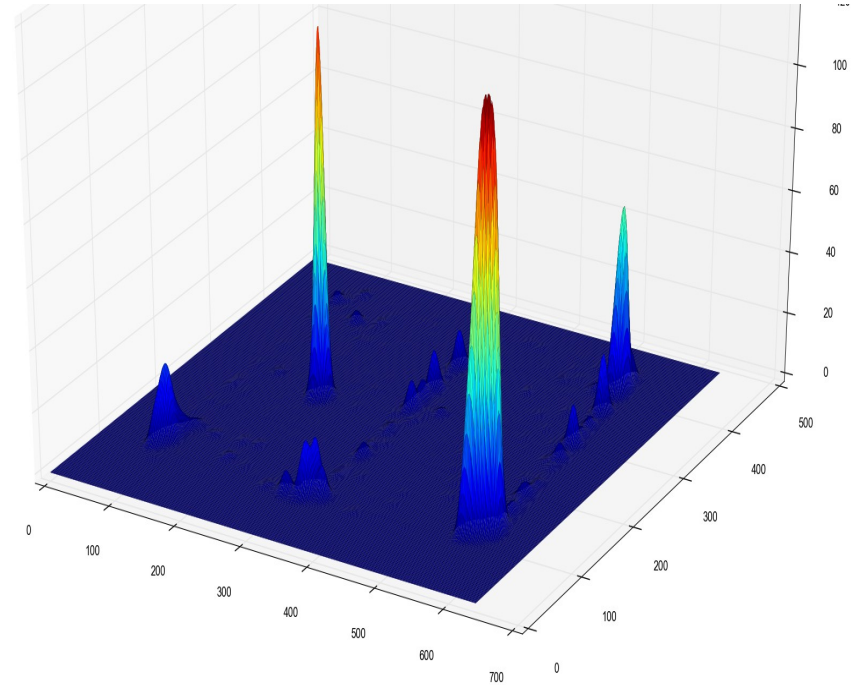
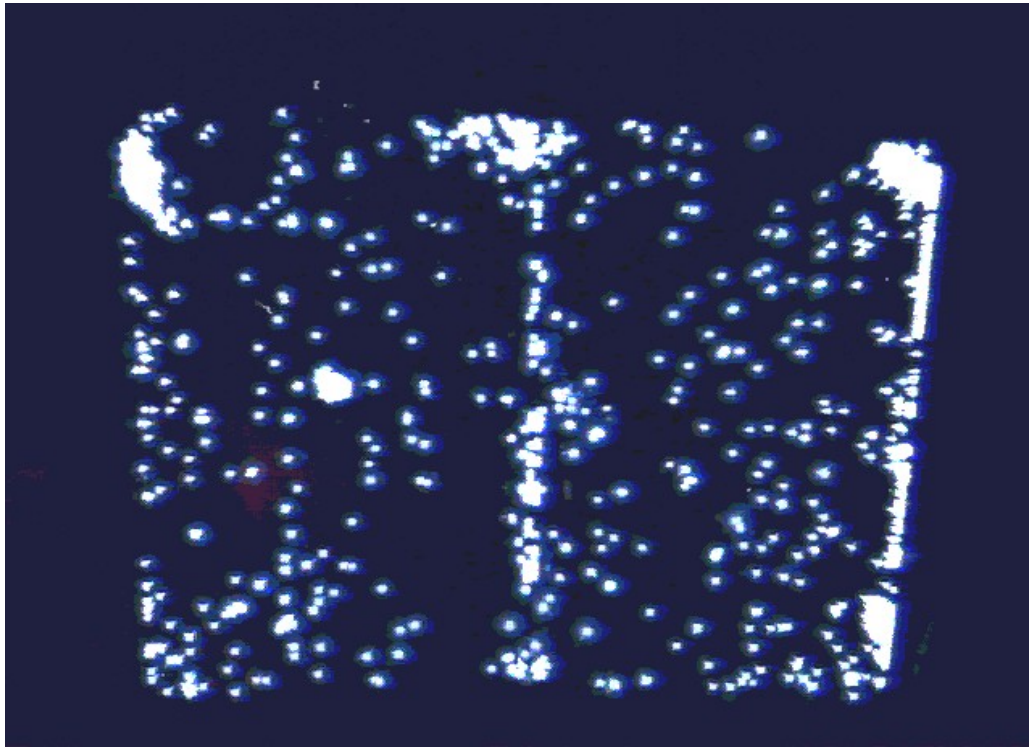
# Repetition of the test (about 150,000 discharges)



- About 150,000 discharges.
- Stage of testing the protective circuit
- Sector died at the end



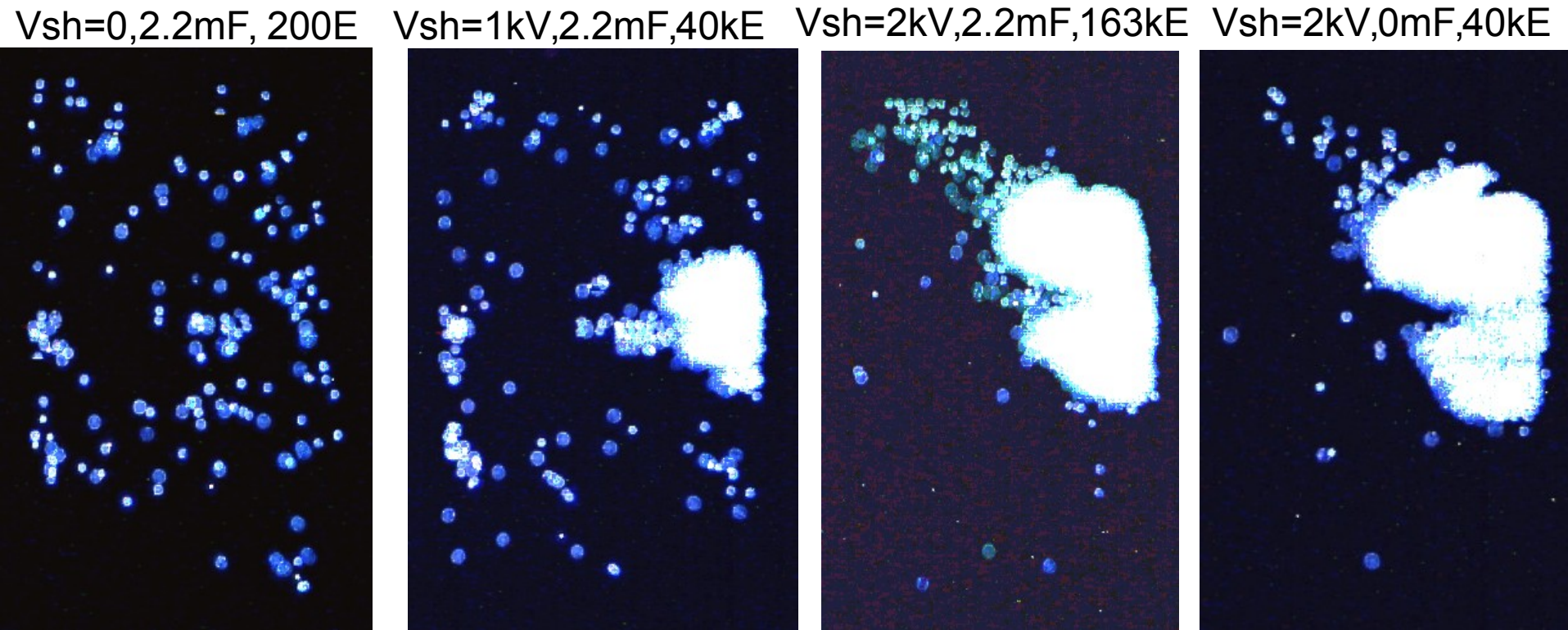
# Results for 4 sector GEM



- have done a long term study with a full sector and with additional protective circuit
- have observed  $>10,000$  discharges
- still no damage
- test continues to run



# Results ([http://desy.de/~fedorch/Trip\\_animation/](http://desy.de/~fedorch/Trip_animation/))



## ➤ Why did the sector not burn without protection?

- Is just a luck? Very robust sector
- Influence of the burned area?



# We try to grow oxide layer (3 hours at 200C)

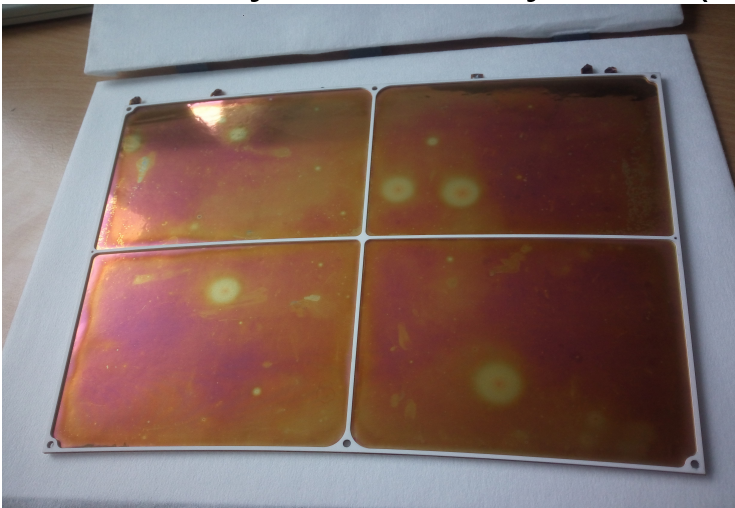
➤ Presumably covered by CuO(black)



➤ Presumably trace of previous sparks



➤ Presumably covered by Cu<sub>2</sub>O(red)

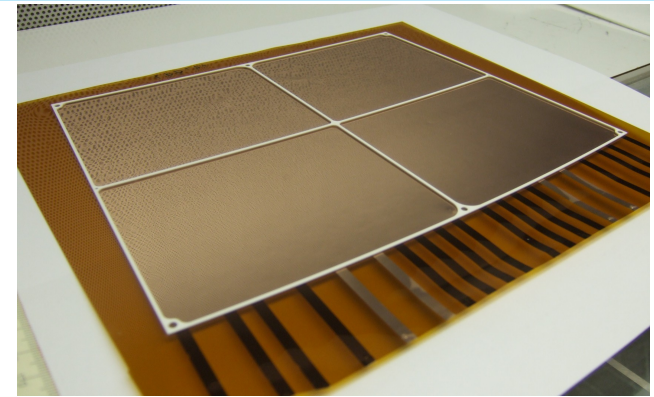
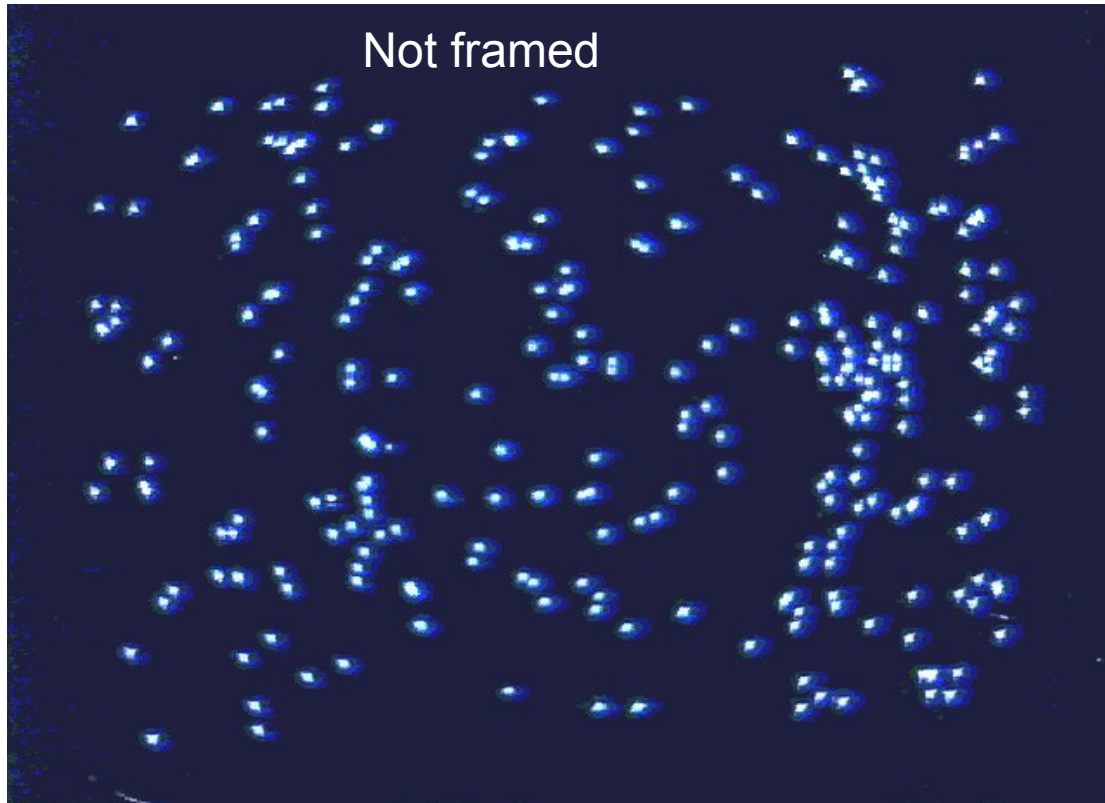


➤ First example is stable after >10ksp

➤ Next example is waiting for testing

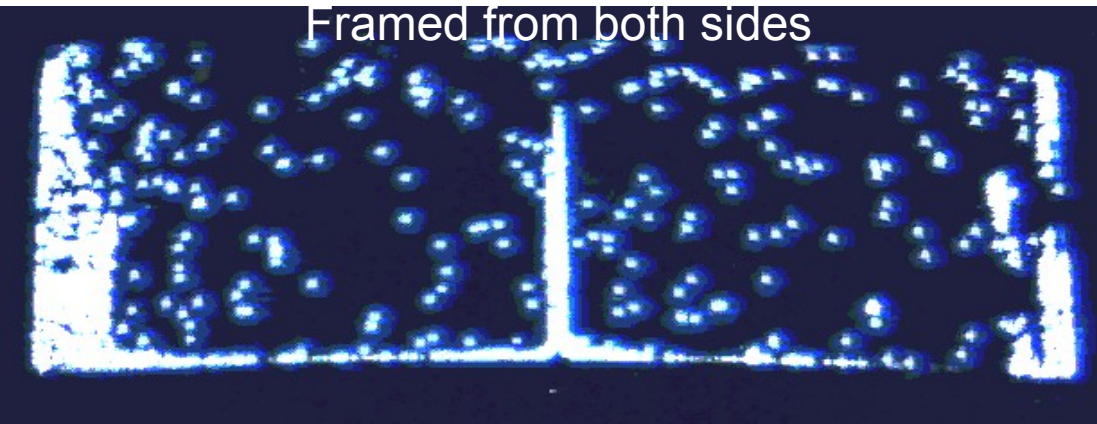
# Impact of the Module Mechanics

Not framed



- Unframed GEM.
- 247 events at 620 V for 20 hours. **4 Sectors**
- Framed from both sides
- 2503 events at 600 V for 24 hours. 2 Sectors

Framed from both sides



- Voltage oscillations in GEM:
  - We see multiple discharges ( $\sim 100\text{ns}$  time difference).
  - We see and simulate voltage oscillations directly after a discharge.
  - These oscillations have been created by an electromagnetic wave in GEM by a discharge.
  - We see an evidence that filtering of the oscillations changes the rate of multiple discharges.
  
- We see evidence that additional protective circuit significantly reduces destructive impact of discharges
  - further validation is needed
  
- Impact of ceramic frames on discharges has been observed
  - Further studies are needed to quantify this.
  - This might imply changes to the building procedure of the module



# Summary(II). Protective mechanisms

## > Protective capacitor

- Dump oscillations. If length of a discharge is bigger then  $\sim 10\text{ns}$  then oscillations force current oscillations that presumably cause destruction. Measurements of discharge is needed.

## > Coating of less conductive material:

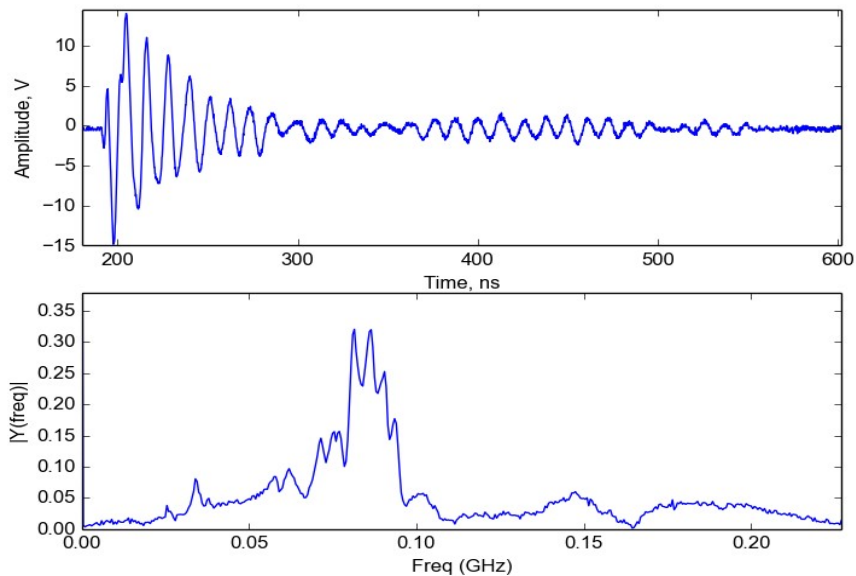
- GEM oxidation. Couple of hours in  $T \geq 200$ .
- High cleanliness is needed to avoid “pictures” on GEM surface.
- More GEMs need to be tested for validation.



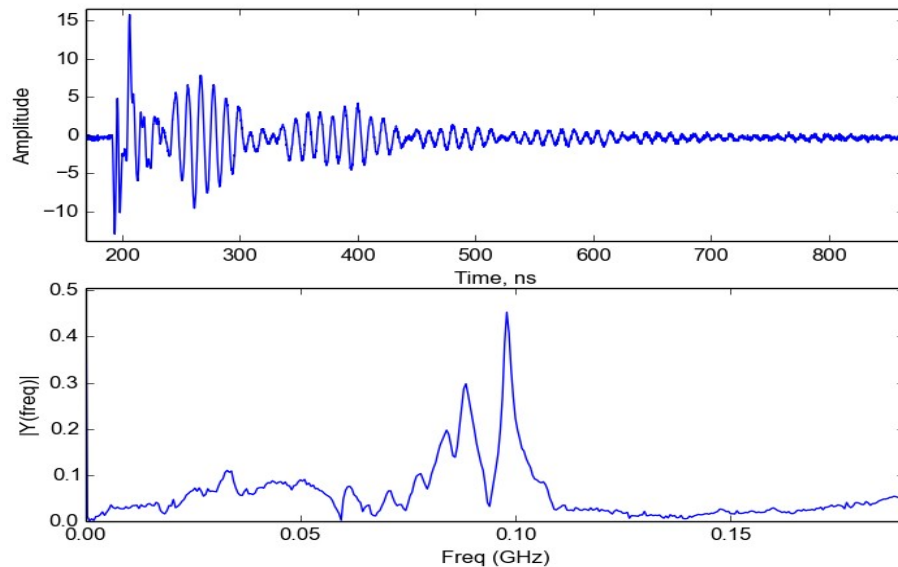


# Fourier transformation

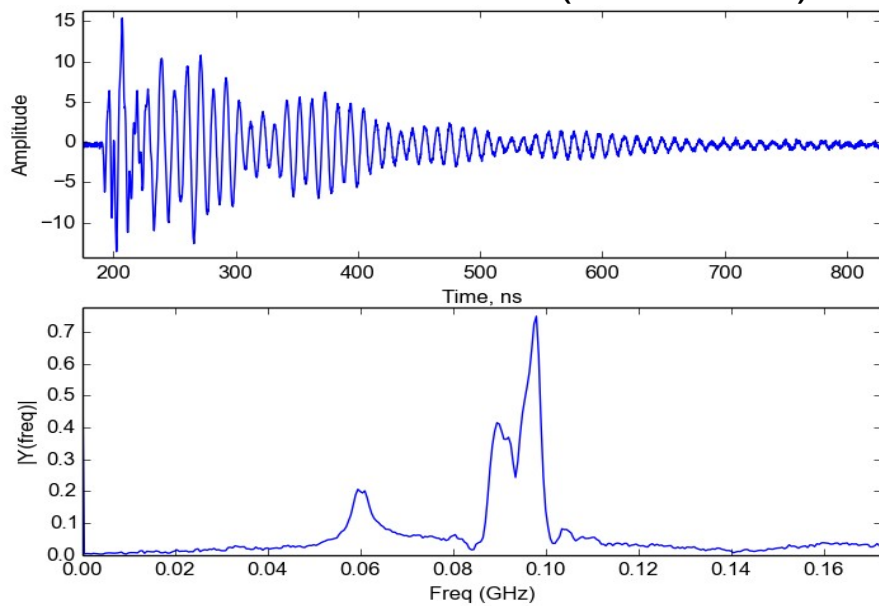
## 10x10cm GEM



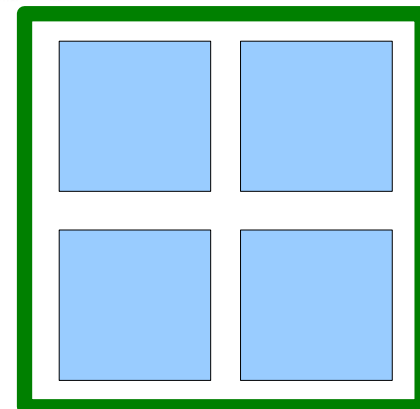
## Sector electrode (~11x9cm)



## Common electrode (~22x18cm)

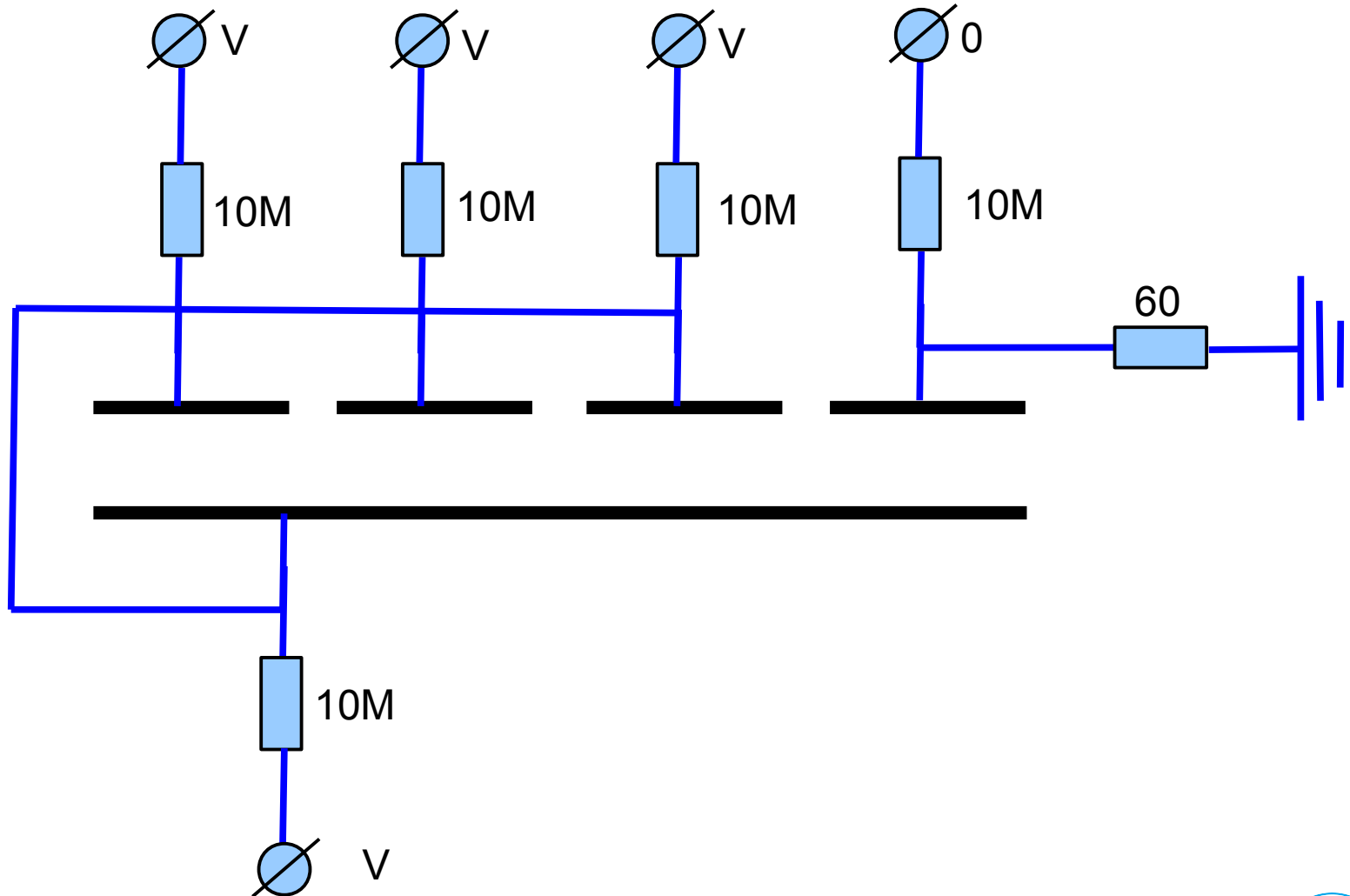


- TDS 3054b
- 500MHz bandwidth
- 5GS/s
- 50Ohm load
- 100x attenuator
- Multiple modes for single sector
- Low frequency for common

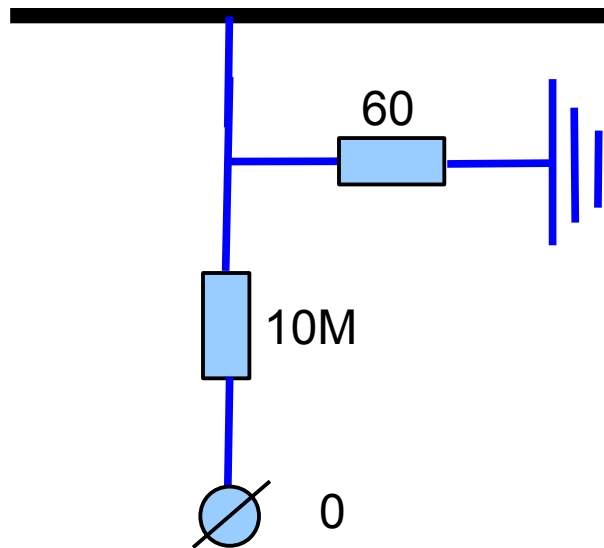
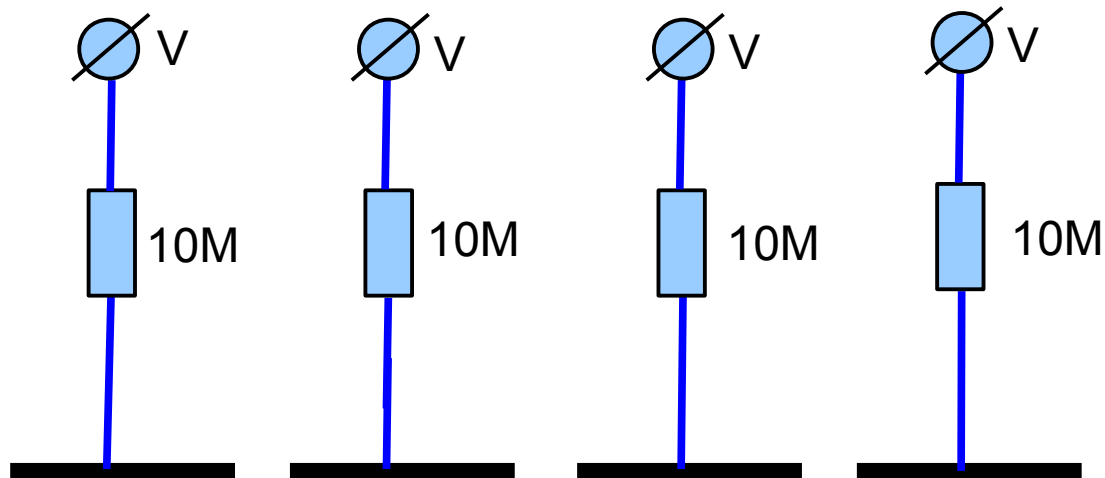




# Scheme of the setup



# Scheme of the setup

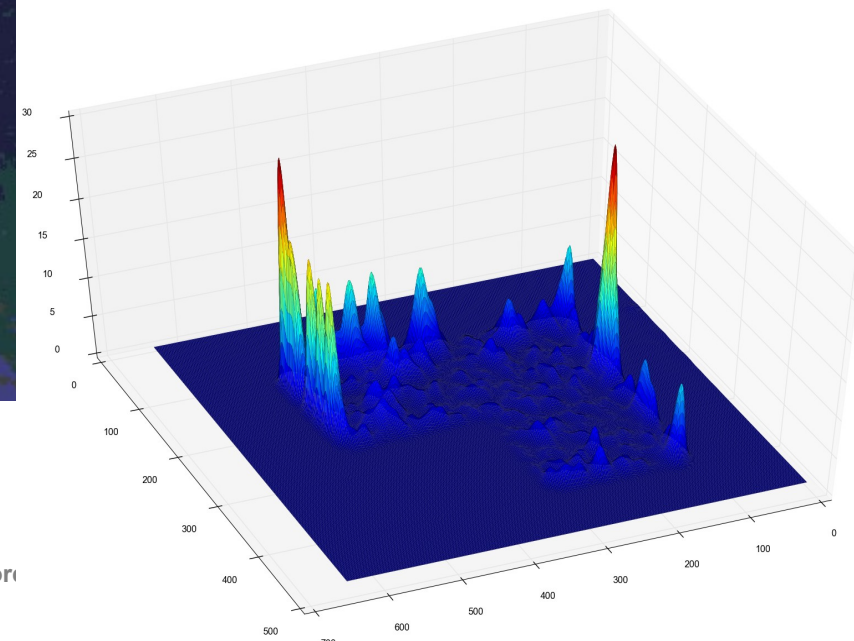
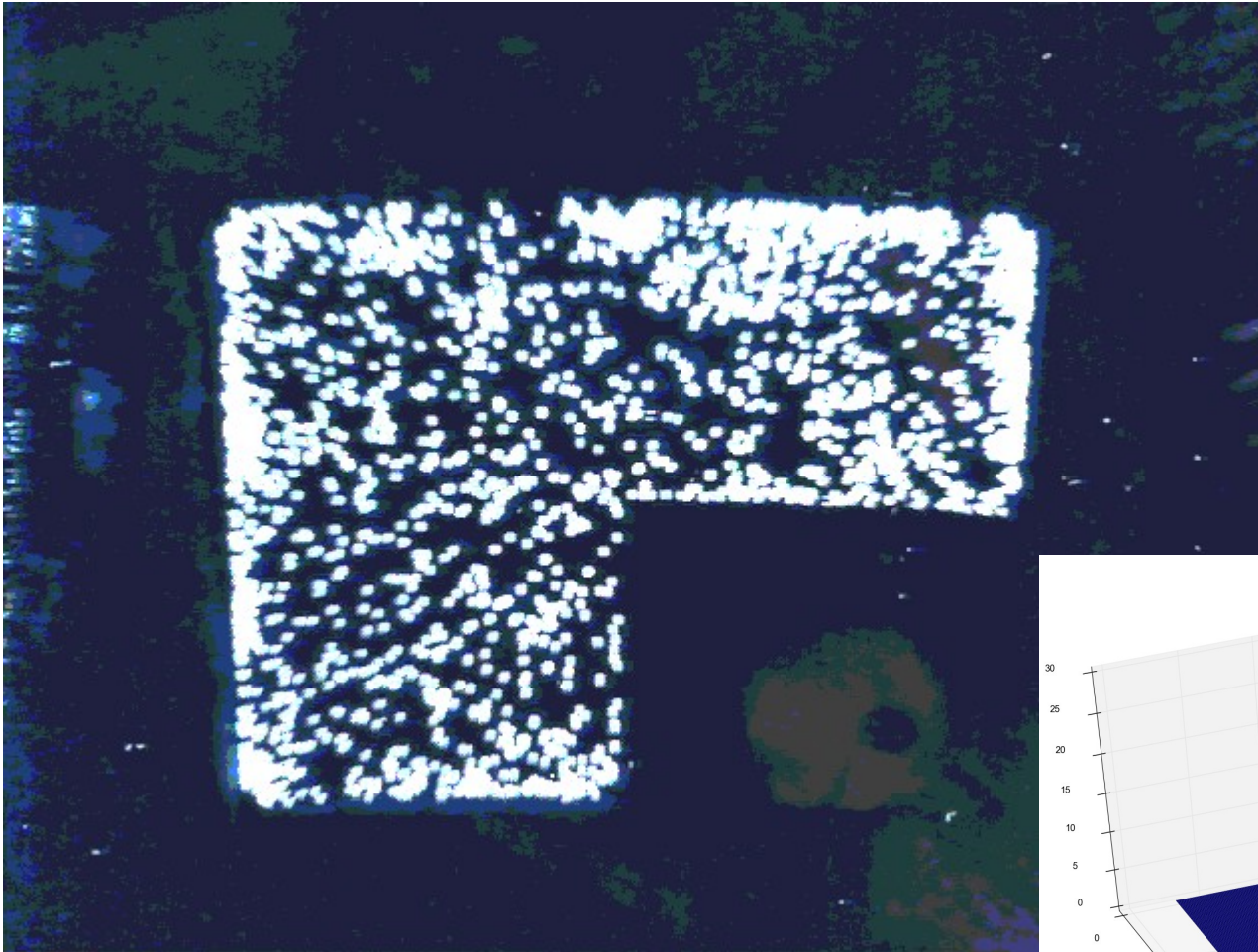


- > 1000 discharges with 2 sectors (without consequences) up to 740V
- > ~10,000 discharges with 4 sectors up to 700V

# Discharges statistic (RC-filter company)

5573 trips has been detected. The fatal trip is a usual single trip.

- > 1-488: <640V
- > 489-849: 640V
- > 850-1688: 660V
- > 1689-3707: 680V
- > 3708-5573: 700V

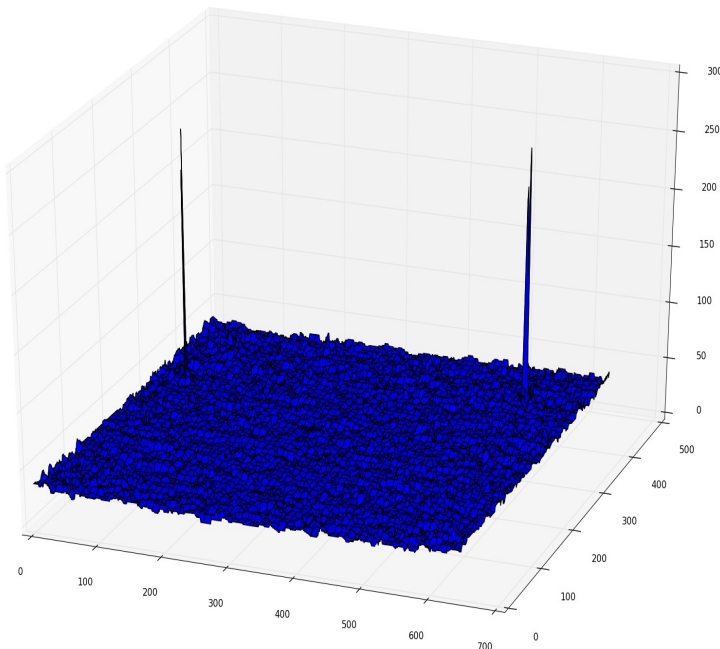


Further testings show that problem has not been solved

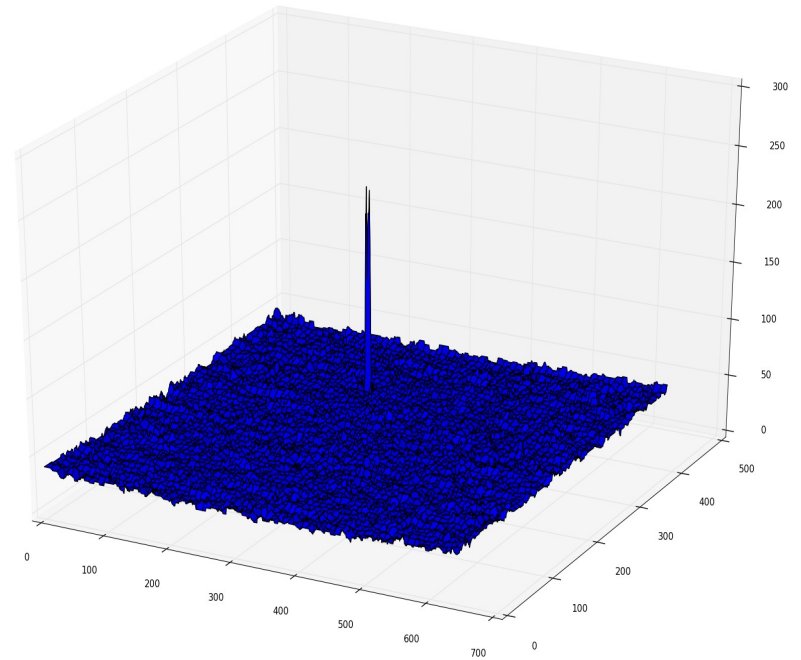
# Using brightness distribution

Trip brightness spikes response for trip light

Double trip



Single trip

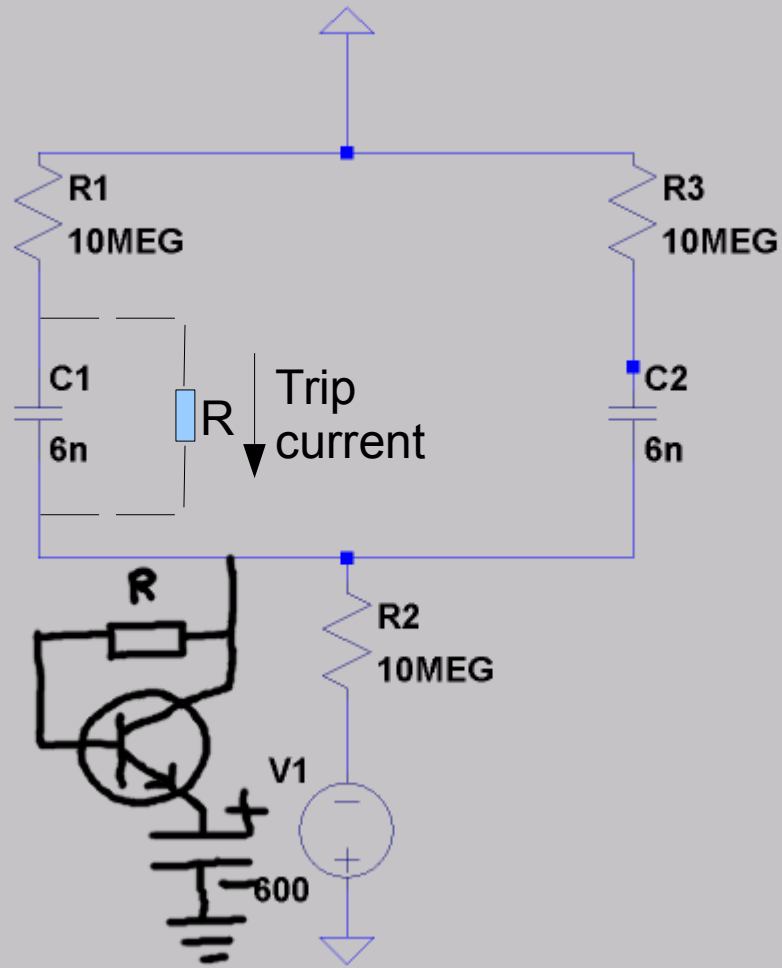


# No comments

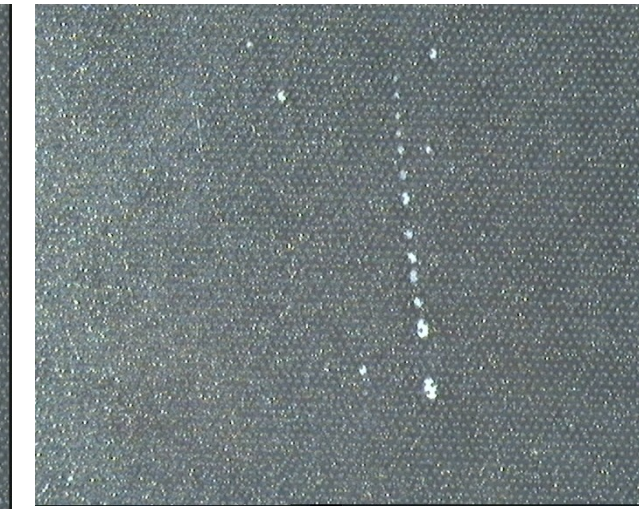
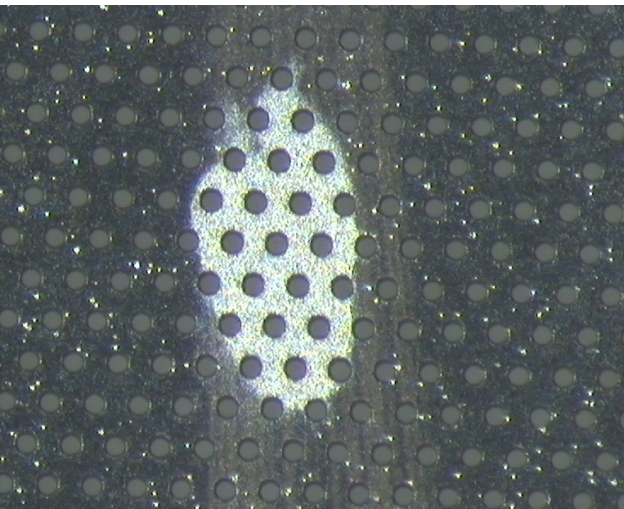
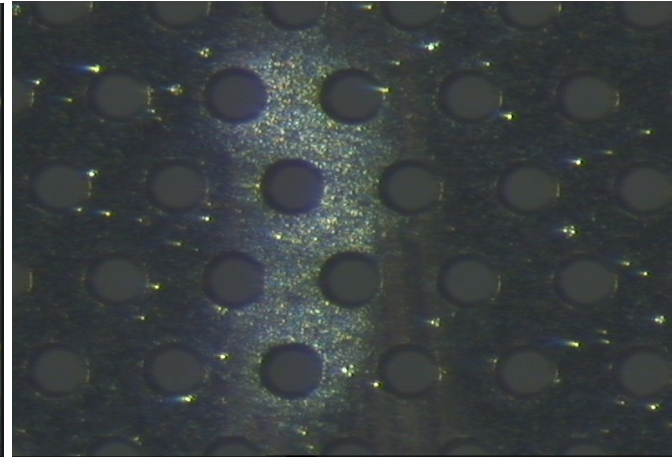
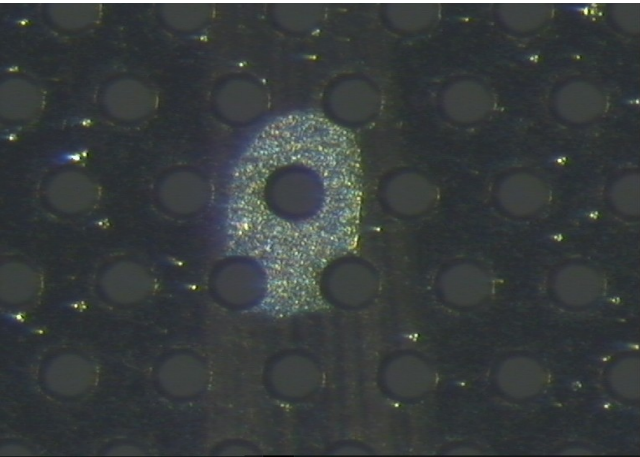




# Possible rescue system

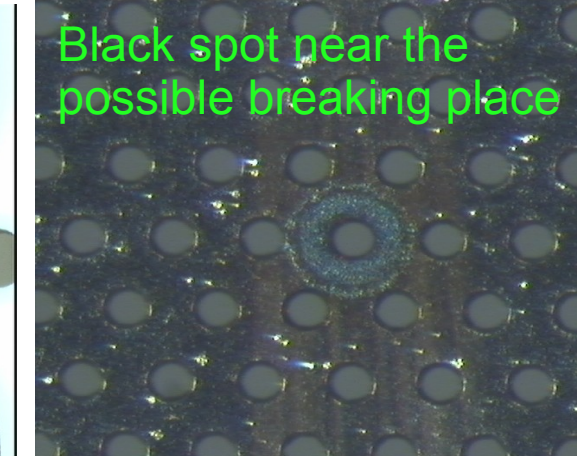
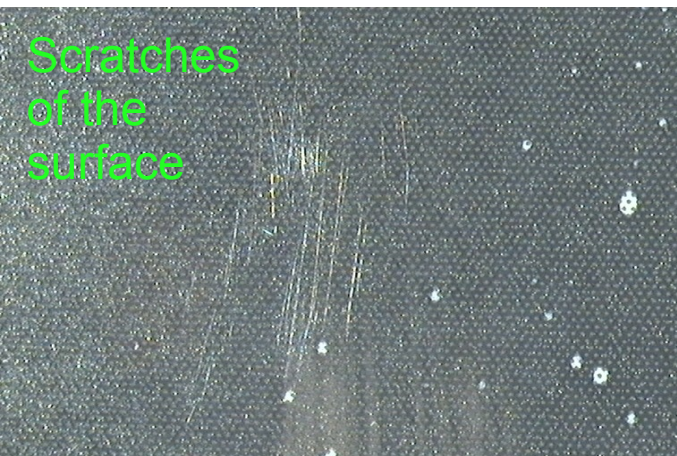
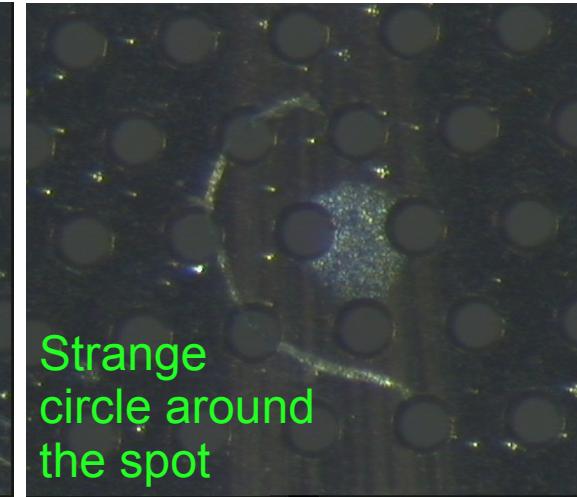
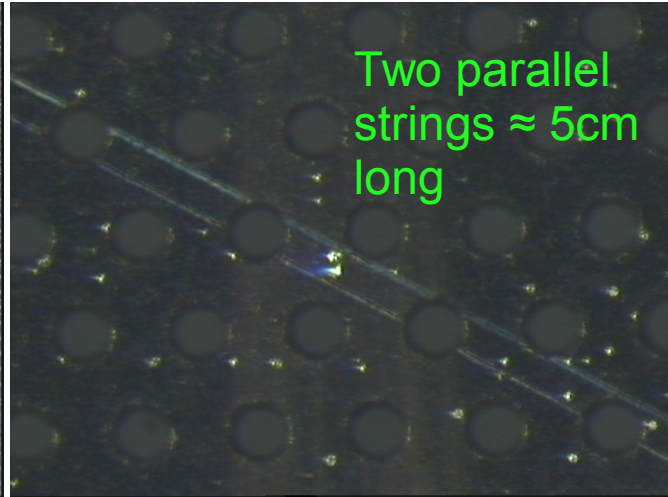
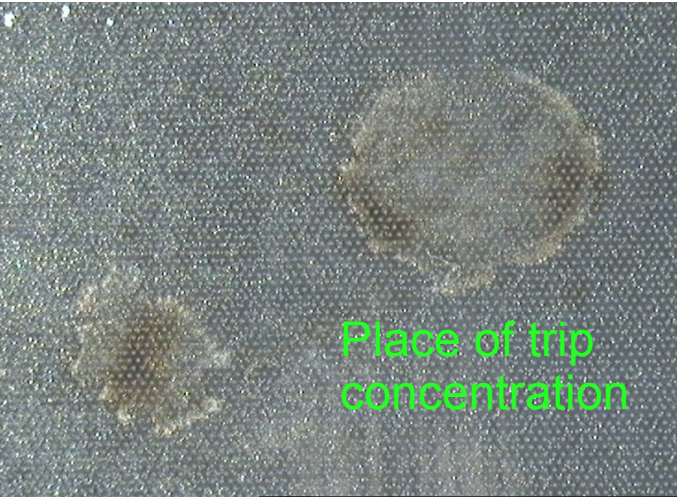


# Bright spots

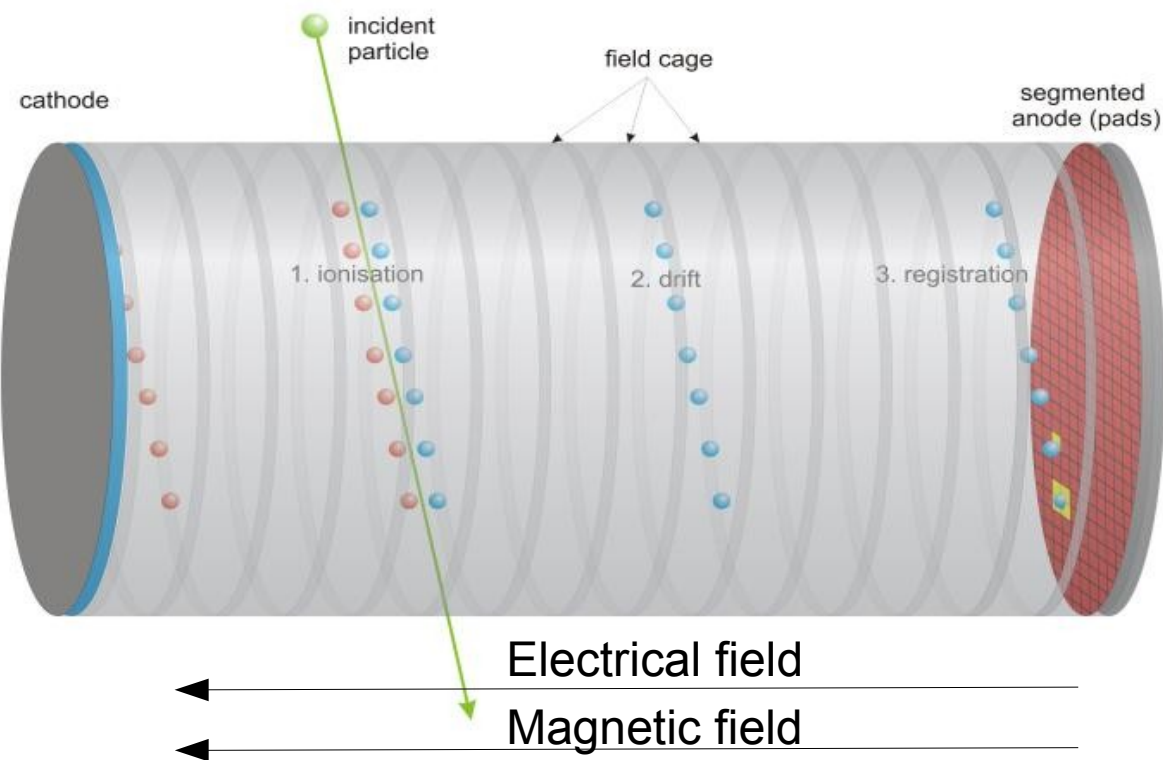




# Other imperfections



# Time Projection Chamber (TPC) concept



> Charged particles leave an electron - ion track.

> Electrons drifting in an electrical field to the anode.

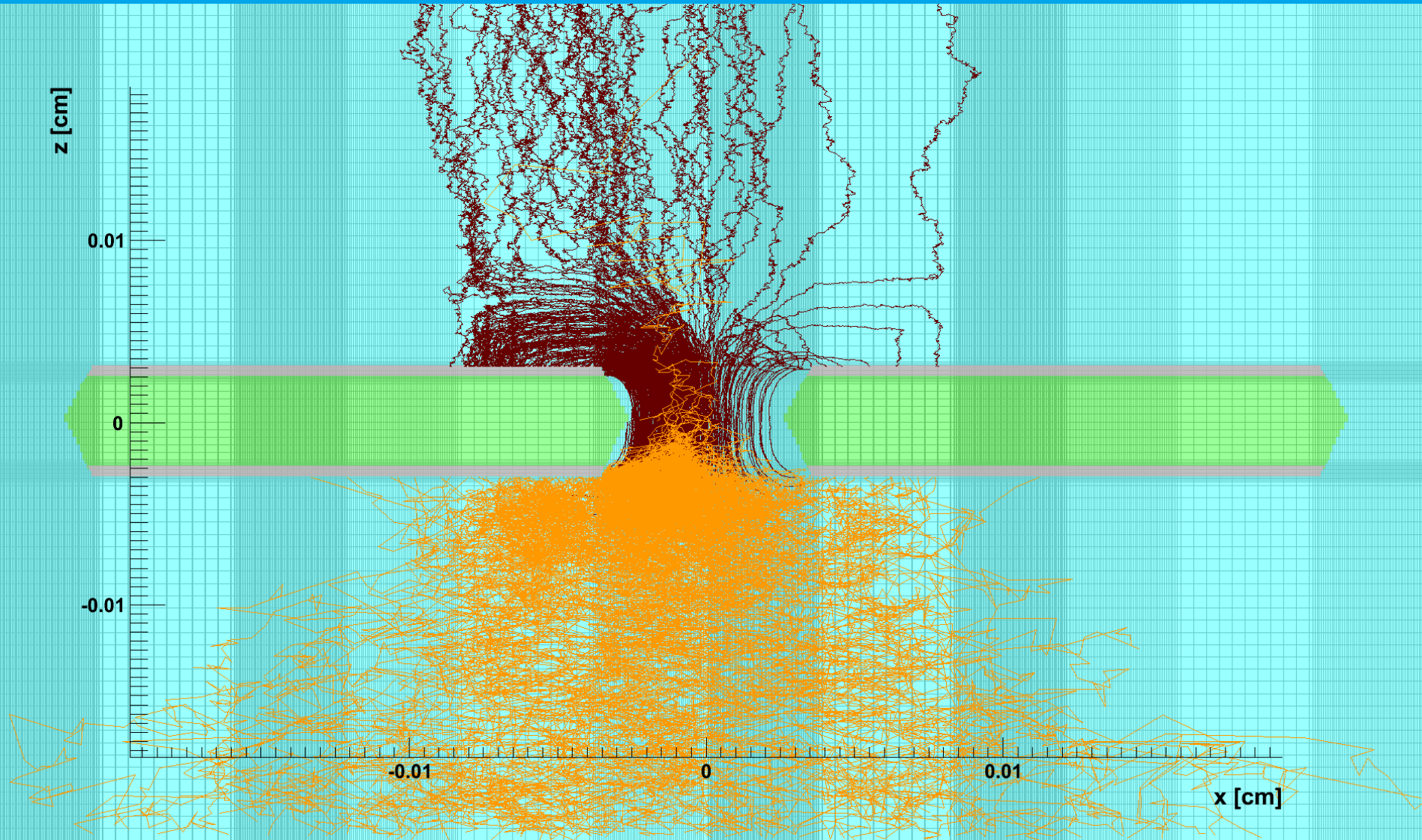
> The 2D trace is recorded by the sensitive part of anode.

> The 3rd dimension is reconstructed with time-of-arrival information

- Planned sizes for the ILC:  $r = 1.8\text{m}$ ,  $z = 4.7\text{m}$
- Readout pad size:  $5.85\text{mm} \times 1.05\text{mm}$
- Required precision:  $r \ \varphi = 60\text{-}100 \ \mu\text{m}$ ,  $z = 0.4\text{-}1.4 \ \text{mm}$

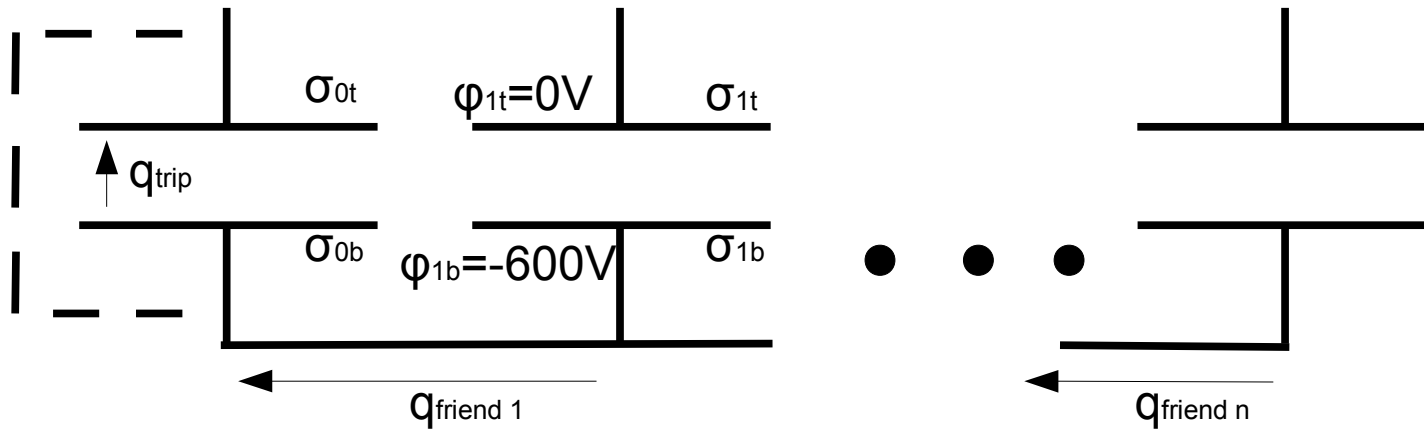


# Gas Electron Multipliers (GEM) simulations

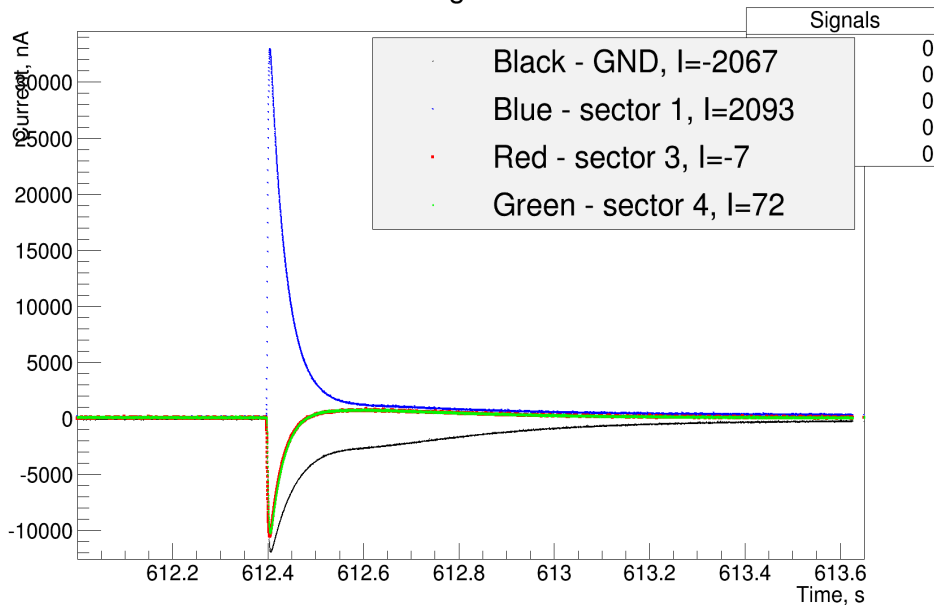




# Usual trips



Signals



- Electrode spectators shows total zero current
- Splash and tripped electrode has opposite sign and equal value of charge exchanging

